
FOREWORD

Special Section on Dependable Computing

Special Sections on Dependable Computing issue is meant to promote the development of the research in the field of dependable computing. This research field is important in order to develop “dependable” systems as computing systems are becoming large and complex due to the improvements in computing and Internet technology.

Last year The 18th Pacific Rim International Symposium on Dependable Computing (PRDC2012), The 21st Asian Test Symposium (ATS2012) and The 13th Workshop on RTL and High Level Testing (WRTL2012) were held in Niigata, Japan. Following the great success of these three conferences the editorial committee of this special issue was organized with the objective of introducing the readers of this journal the research activities in this area.

As a result of the call for papers for the current special sections, we received 32 submissions by the submission deadline, from 5 countries and regions, with the following distribution of countries: 23 from Japan, 4 from China, 2 from Korea, and 1 each from Taiwan, India and Canada.

Each submission was handled by an associate editor, where the full paper and the letter were peer-reviewed by two designated reviewers and one designated reviewer, respectively. Based on both review results by reviewers and the recommendation by an associate editor, we held three face-to-face guest-editorial meetings of this special section on January 24, 2013, March 2, 2013 and May 25, 2013, and discussed the status of each submission very carefully.

Finally, we accepted 13 full papers and 4 letters for this issue, where the acceptance rate was 53%. We are proud to have accepted the very high quality papers for the special section of this transaction. Clearly much time and effort were spent by the 17 guest-associate editors and our expert reviewers. Unfortunately, some of high quality papers could not be accepted due to the strict publication schedule and the IEICE editorial policy that two more revisions are not allowed. We expect these authors to submit their revised papers to the regular issues in the IEICE Transactions in the future.

Finally, not only reviewing and selecting papers but also communicating with the associate editors, reviewers and authors have been an overwhelming task. I would like to express my sincere appreciation and gratitude to all authors of submitted papers, the members of the editorial committee, and all the reviewers for their cooperation. No words can express our gratitude to the Guest Secretary; Professor Tadashi Dohi, Hiroshima University, Japan and the two Guest Vice Secretaries; Professor Toshinori Hosokawa, Nihon University, Japan and Professor Hideyuki Ichihara, Hiroshima City University, Japan for their excellent jobs.

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Hiroshi Takahashi (Ehime Univ.), Guest Editor-in-Chief

Hiroshi Takahashi (*Member*) received his B. E. and M. E. degrees in Electronic Engineering from Saga University, Saga, Japan in 1988 and 1990, respectively. He received his Dr. degree from Ehime University, Japan in 1996. From 2000 to 2009 he was an Associate Professor in the Department of Electrical and Electronic Engineering and Computer Science, Graduate School of Science and Engineering, Ehime University. Since 2010, he has been a Full Professor at Ehime University. From May 2000 to March 2001, he was a research fellow in the University of Wisconsin-Madison, USA. He received the IEICE Best Paper Award in 2011. His research interests are test generation and fault diagnosis for digital systems. Dr. Takahashi is a senior member of the IEEE and a member of IPSJ. He served as the Program committee member of 2003, 2004, 2007, 2009, 2010, IEEE Asian Test Symposium and as the Program Chair of the 2012 IEEE Asian Test Symposium.

